

**PowerMOS transistor****BUK456-1000A  
BUK456-1000B**

T-39-13

**GENERAL DESCRIPTION**

N-channel enhancement mode field-effect power transistor in a plastic envelope.

The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

**QUICK REFERENCE DATA**

SYMBOL	PARAMETER	BUK456	MAX.	MAX.	UNIT
$V_{DS}$	Drain-source voltage	-1000A	1000	-1000B	V
$I_D$	Drain current (DC)	1000	3.5	1000	A
$P_{tot}$	Total power dissipation	3.1	125	3.1	W
$R_{DS(ON)}$	Drain-source on-state resistance	125	4	125	$\Omega$

**MECHANICAL DATA***Dimensions in mm*

Net Mass: 2g

Pinning:

1 = Gate

2 = Drain

3 = Source

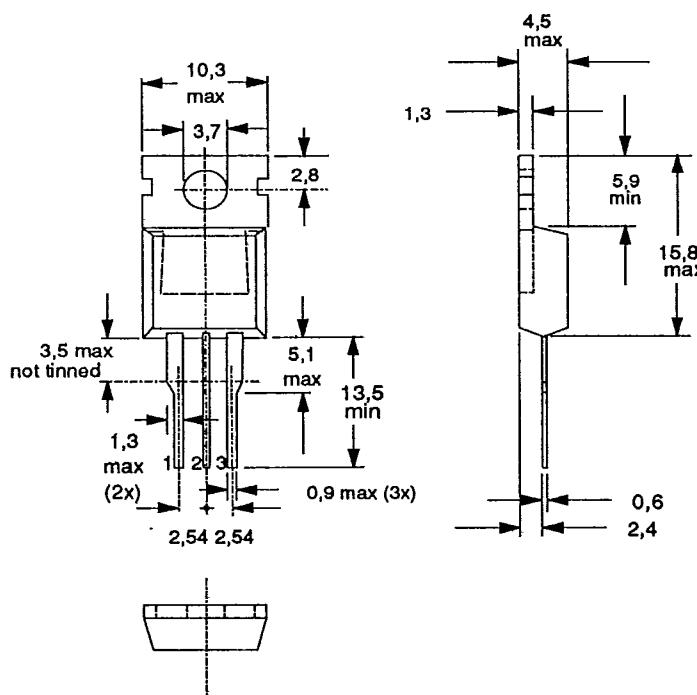
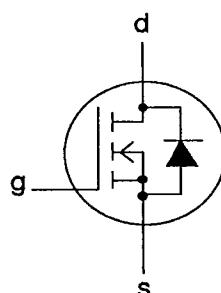


Fig.1 TO220AB; drain connected to mounting base.

**Notes**

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Accessories supplied on request: refer to Mounting instructions for TO220 envelopes.

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**RATINGS**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
$V_{DS}$ $V_{DGR}$ $\pm V_{GS}$	Drain-source voltage	$R_{GS} = 20 \text{ k}\Omega$	-	1000		V
	Drain-gate voltage		-	1000		V
	Gate-source voltage		-	30		V
$I_D$ $I_D$ $I_{DM}$	Drain current (DC)	$T_{mb} = 25^\circ\text{C}$	-	3.5	-1000A	A
	Drain current (DC)		-	2.2	3.1	A
	Drain current (pulse peak value)		-	14	2.0	A
$P_{tot}$ $T_{stg}$ $T_j$	Total power dissipation	$T_{mb} = 25^\circ\text{C}$	-	125		W
	Storage temperature		-55	150		°C
	Junction Temperature		-	150		°C

**THERMAL RESISTANCES**

From junction to mounting base	$R_{th,j-mb} = 1.0 \text{ K/W}$
From junction to ambient	$R_{th,j-a} = 60 \text{ K/W}$

**STATIC CHARACTERISTICS** $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	1000	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 1000 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	-	2	20	$\mu\text{A}$
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 1000 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA
$I_{GSS}$	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
$R_{DS(on)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 1.5 \text{ A}$ BUK456-1000A	-	3.5	4.0	$\Omega$
		$I_D = 1.5 \text{ A}$ BUK456-1000B	-	4.5	5.0	$\Omega$

**DYNAMIC CHARACTERISTICS** $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 1.5 \text{ A}$	3.0	4.3	-	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	1000	1250	pF
$C_{iss}$ $C_{oss}$ $C_{rss}$			-	80	120	pF
$C_{iss}$ $C_{oss}$ $C_{rss}$			-	30	50	pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	$V_{DD} = 30 \text{ V}; I_D = 2.3 \text{ A};$ $V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega;$ $R_{gen} = 50 \Omega$	-	10	25	ns
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$			-	25	40	ns
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$			-	130	150	ns
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$			-	40	60	ns
$L_d$	Internal drain inductance	Measured from contact screw on tab to centre of die	-	3.5	-	nH
$L_d$	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
$L_s$	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

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**REVERSE DIODE RATINGS AND CHARACTERISTICS** $T_{mb} = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_{DR}$	Continuous reverse drain current	-	-	-	3.5	A
$I_{DRM}$	Pulsed reverse drain current	-	-	-	14	A
$V_{SD}$	Diode forward voltage	$I_F = 3.5 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.0	1.3	V
$t_{rr}$ $Q_{rr}$	Reverse recovery time Reverse recovery charge	$I_F = 3.5 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V}; V_R = 100 \text{ V}$	-	1800 12	-	ns $\mu\text{C}$

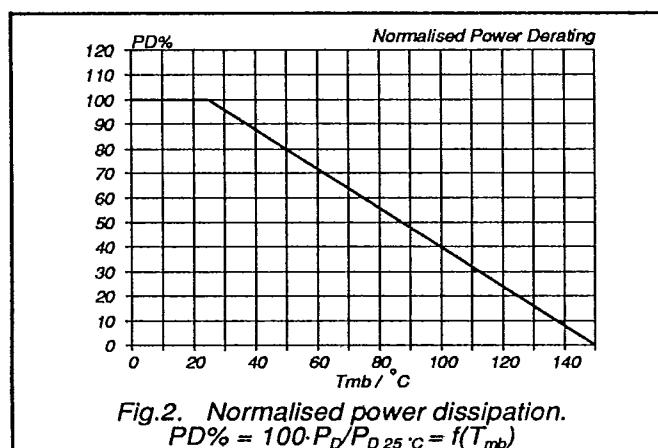


Fig.2. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D / P_{D, 25^\circ\text{C}} = f(T_{mb})$

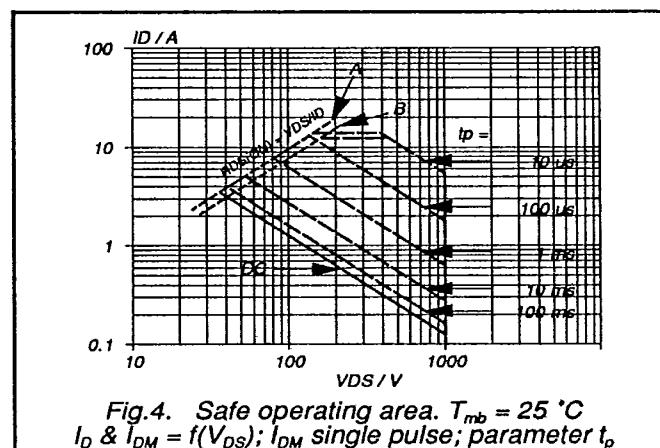


Fig.4. Safe operating area.  $T_{mb} = 25^\circ\text{C}$   
 $I_D \& I_{DM} = f(V_{DS}); I_{DM}$  single pulse; parameter  $t_p$

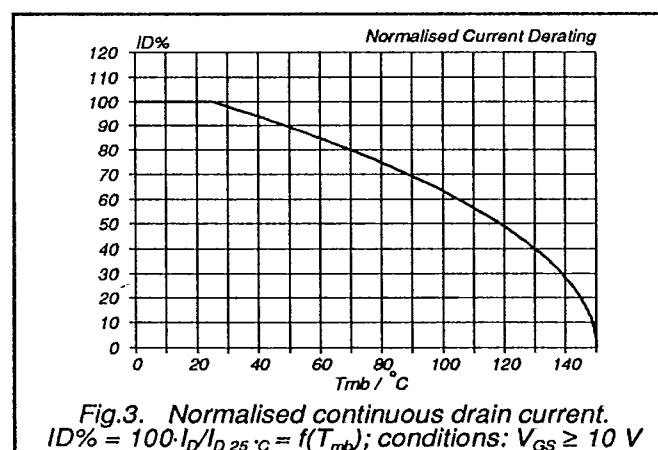


Fig.3. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D / I_{D, 25^\circ\text{C}} = f(T_{mb}); \text{conditions: } V_{GS} \geq 10 \text{ V}$

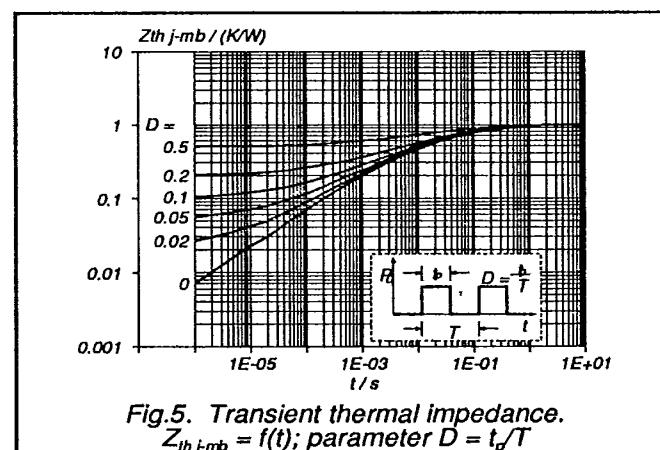


Fig.5. Transient thermal impedance.  
 $Z_{th,j-mb} = f(t); \text{parameter } D = t_p/T$

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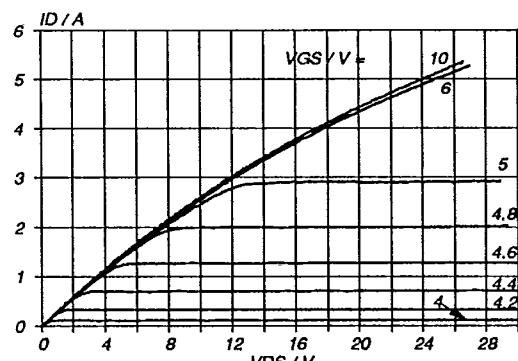


Fig.6. <sup>1</sup> Typical output characteristics,  $T_J = 25^\circ\text{C}$ .  
 $I_D = f(V_{DS})$ ; parameter  $V_{GS}$

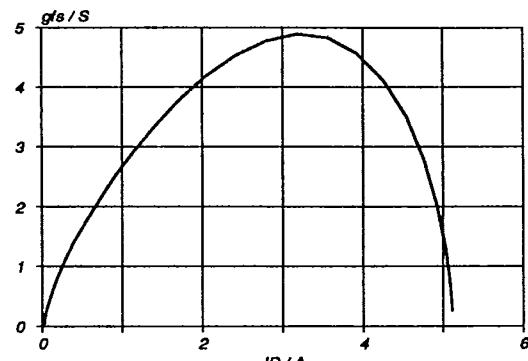


Fig.9. Typical transconductance,  $T_J = 25^\circ\text{C}$ .  
 $g_{fs} = f(I_D)$ ; conditions:  $V_{DS} = 25\text{ V}$

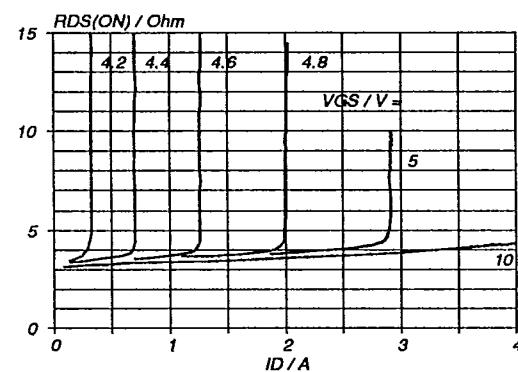


Fig.7. Typical on-state resistance,  $T_J = 25^\circ\text{C}$ .  
 $R_{DS(ON)} = f(I_D)$ ; parameter  $V_{GS}$

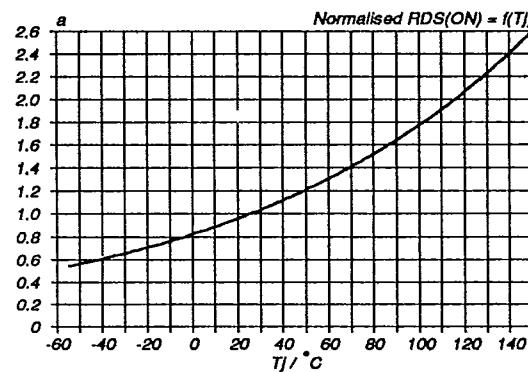


Fig.10. Normalised drain-source on-state resistance.  
 $a = R_{DS(ON)}/R_{DS(ON)25^\circ\text{C}} = f(T_J)$ ;  $I_D = 1.5\text{ A}$ ;  $V_{GS} = 10\text{ V}$

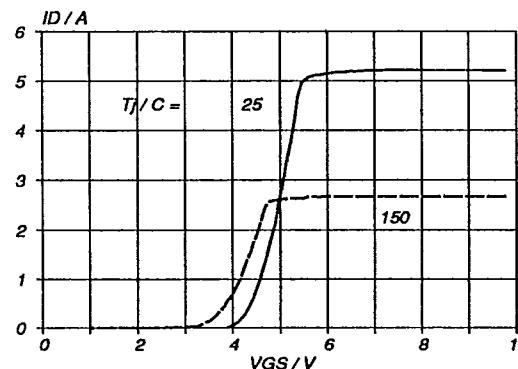


Fig.8. Typical transfer characteristics.  
 $I_D = f(V_{GS})$ ; conditions:  $V_{DS} = 25\text{ V}$ ; parameter  $T_J$

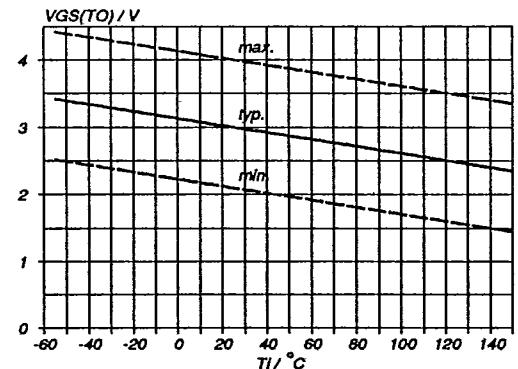


Fig.11. Gate threshold voltage.  
 $V_{GS(TO)} = f(T_J)$ ; conditions:  $I_D = 1\text{ mA}$ ;  $V_{DS} = V_{GS}$

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